

HM6716, HM6719 Series

T-46-23-12

2048-word × 8-bit High Speed Hi-BiCMOS Static RAM (with OE)

2048-word × 9-bit High Speed Hi-BiCMOS Static RAM

HITACHI/ LOGIC/ARRAYS/MEM

Features

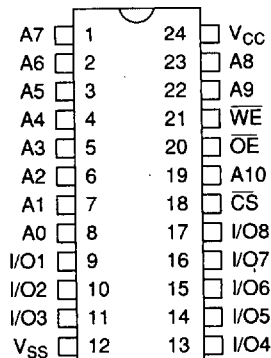
- Fast access time: 25/30 ns (max)
- Low power dissipation (DC): 280 mW (typ)
- +5 V single supply
- Completely static memory
- No clock or timing strobe required
- Fully TTL compatible input and output

Pin Arrangement

Ordering Information

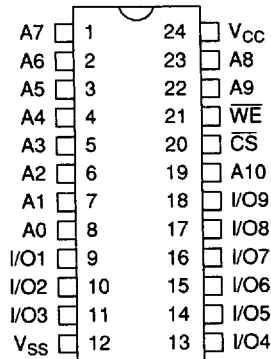
Type No.	Access time	Package
HM6716P-25	25 ns	300-mil 24-pin
HM6716P-30	30 ns	plastic DIP (DP-24NC)
HM6719P-25	25 ns	
HM6719P-30	30 ns	

HM6716 Series



(Top view)

HM6719 Series

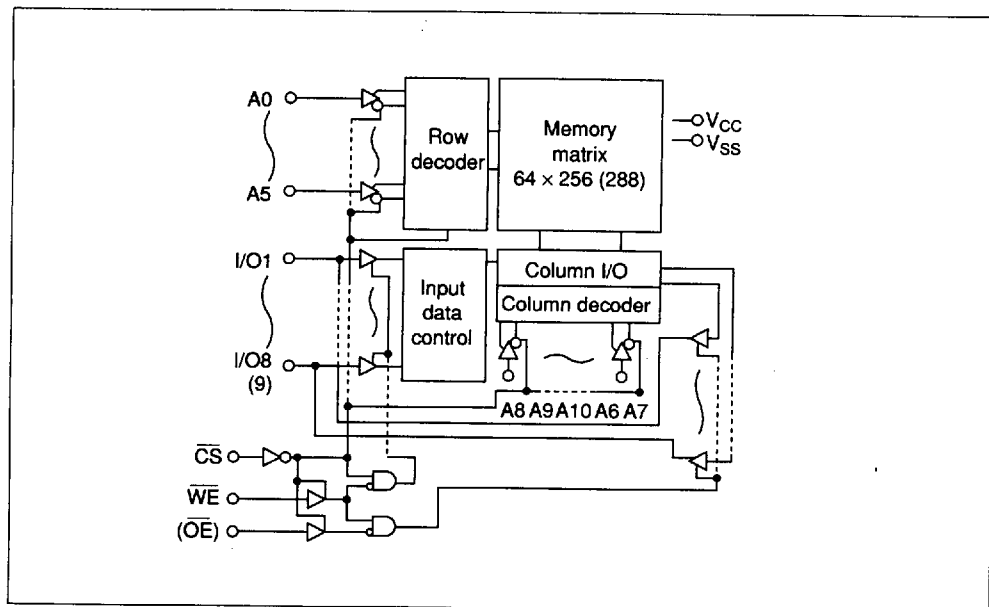


(Top view)

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Block Diagram



Truth Table (HM6716)

$\overline{CS}$	$\overline{OE}$	$\overline{WE}$	Mode	V_{CC} Current	Pin	Reference cycle
H	H or L	H or L	Not selected	I_{SB}, I_{SB1}	High Z	—
L	L	H	Read	I_{CC}, I_{CC1}	Dout	Read cycle 1–3
L	H	L	Write	I_{CC}, I_{CC1}	Din	Write cycle 1
L	L	L	Write	I_{CC}, I_{CC1}	Din	Write cycle 2
L	H	H	Output disabled	I_{CC}, I_{CC1}	High Z	—

Truth Table (HM6719)

$\overline{CS}$	$\overline{WE}$	Mode	V_{CC} current	Pin	Reference cycle
H	H or L	Not selected	I_{SB}, I_{SB1}	High Z	—
L	H	Read	I_{CC}, I_{CC1}	Dout	Read cycle 2, 3
L	L	Write	I_{CC}, I_{CC1}	Din	Write cycle 1

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Absolute Maximum Ratings

Parameter	Symbol	Rating	Unit
Terminal voltage to V_{SS} pin	V_T	-0.5 to +7.0	V
Power dissipation	P_T	1.0	W
Operating temperature range	T_{opr}	0 to +70	°C
Storage temperature range	T_{stg}	-55 to +125	°C
Storage temperature range (with bias)	$T_{stg} (bias)$	-10 to +85	°C

Recommended DC Operating Conditions ($T_a = 0$ to +70°C)

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V_{CC}	4.5	5.0	5.5	V
	V_{SS}	0	0	0	V
Input high voltage	V_{IH}	2.2	—	6.0	V
Input low voltage	V_{IL}^*	-3.0	—	0.8	V

Note: Pulse width: 20 ns, DC: -0.5 V

DC Characteristics ($V_{CC} = 5\text{ V} \pm 10\%$, $T_a = 0$ to +70°C)

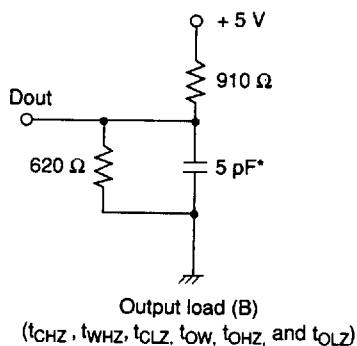
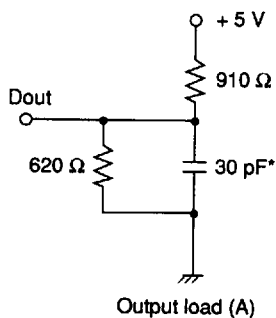
Parameter	Symbol	Min	Typ	Max	Unit	Test condition
Input leakage current	$ I_{II} $	—	—	2	μA	$V_{CC} = 5.5\text{ V}$, $V_{IN} = V_{SS}$ to V_{CC}
Output leakage current	$ I_{LO} $	—	—	2	μA	$\overline{CS} = V_{IH}$, $V_{VO} = V_{SS}$ to V_{CC}
Operating power supply current	I_{CC}	—	—	120	mA	$\overline{CS} = V_{IL}$, $I_{VO} = 0\text{ mA}$
Average operating current	I_{CC1}	—	—	130	mA	Min. cycle, duty: 100%, $I_{VO} = 0\text{ mA}$
Standby power supply current	I_{SB}	—	—	30	mA	$\overline{CS} = V_{IH}$
	I_{SB1}	—	—	10	mA	$\overline{CS} \geq V_{CC} - 0.2\text{ V}$ $V_{IN} \leq 0.2\text{ V}$ or $V_{IN} \geq V_{CC} - 0.2\text{ V}$
Output low voltage	V_{OL}	—	—	0.4	V	$I_{OL} = 4\text{ mA}$
Output high voltage	V_{OH}	2.4	—	—	V	$I_{OH} = -1.0\text{ mA}$

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AC Test Conditions:

- Input pulse levels: V_{SS} to 3.0 V
- Input and output reference levels: 1.5 V
- Input rise and fall time: 4 ns
- Output load: see figure



Note: Including scope and jig

Capacitance ($T_a = 25^\circ\text{C}$, $f = 1.0\text{ MHz}$)

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Input capacitance	C_{IN}	$V_{IN} = 0\text{ V}$	—	—	6	pF
I/O capacitance	$C_{I/O}$	$V_{I/O} = 0\text{ V}$	—	—	8	pF

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AC Characteristics (V_{CC} 5 V $\pm$ 10%, T_a = 0 to +70°C, unless otherwise noted.)

Read Cycle

Parameter	Symbol	HM6716-25 HM6719-25		HM6716-30 HM6719-30		Unit	Notes
		Min	Max	Min	Max		
Read cycle time	t_{RC}	25	—	30	—	ns	—
Address access time	t_{AA}	—	25	—	30	ns	—
Chip select access time	t_{ACS}	—	25	—	30	ns	—
Chip selection to output in low Z	t_{CLZ}	0	—	0	—	ns	2
Output enable to output valid	t_{OE}	0	20	0	20	ns	1
Output enable to output in low Z	t_{OLZ}	0	—	0	—	ns	1, 2
Chip deselction to output in high Z	t_{CHZ}	0	10	0	12	ns	2
Chip disable to output in high Z	t_{OHZ}	0	10	0	10	ns	1, 2
Output hold from address change	t_{OH}	5	—	5	—	ns	—
Input voltage rise/fall time	t_T	—	150	—	150	ns	3

Write Cycle

Parameter	Symbol	HM6716-25 HM6719-25		HM6716-30 HM6719-30		Unit	Notes
		Min	Max	Min	Max		
Write cycle time	t_{WC}	25	—	30	—	ns	—
Chip selection to end of write	t_{CW}	20	—	25	—	ns	—
Address setup time	t_{AS}	0	—	0	—	ns	—
Address valid to end of write	t_{AW}	20	—	25	—	ns	—
Write pulse width	t_{WP}	20	—	25	—	ns	—
Write recovery time	t_{WR}	0	—	0	—	ns	—
Output disable to output in high Z	t_{OHZ}	0	10	0	10	ns	1, 2
Write to output in high Z	t_{WHZ}	0	10	0	12	ns	2

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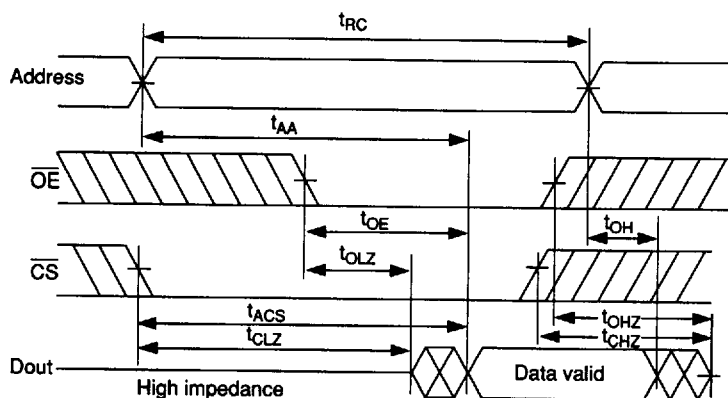
Write Cycle (cont)

Parameter	Symbol	HM6716-25 HM6719-25		HM6716-30 HM6719-30		Unit	Notes
		Min	Max	Min	Max		
Data valid to end of write	t_{DW}	15	—	15	—	ns	—
Data hold time	t_{DH}	5	—	5	—	ns	—
Output active from end of write	t_{OW}	0	—	0	—	ns	2

Note: 1. These parameters are for HM6716.

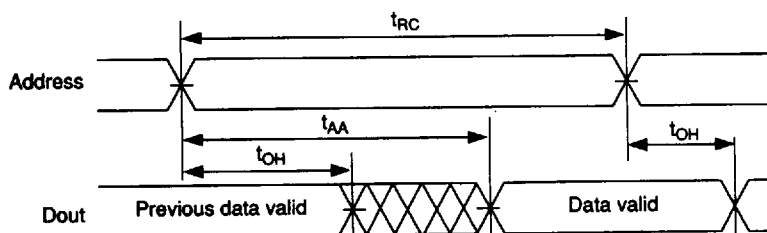
2. Transition is measured ± 200 mV from steady state voltage with load (B). These parameters are sampled and not 100% tested.

3. Please contact your nearest Hitachi Sales Department regarding specifications.

Timing Waveforms**Read Cycle 1**

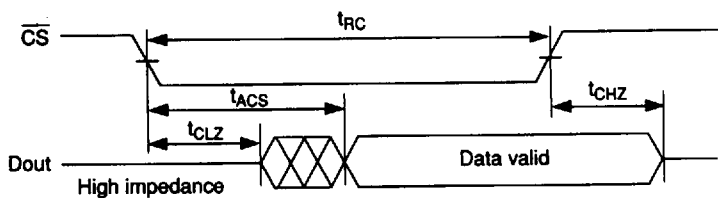
Note: WE is high for read cycle.

Read Cycle 2

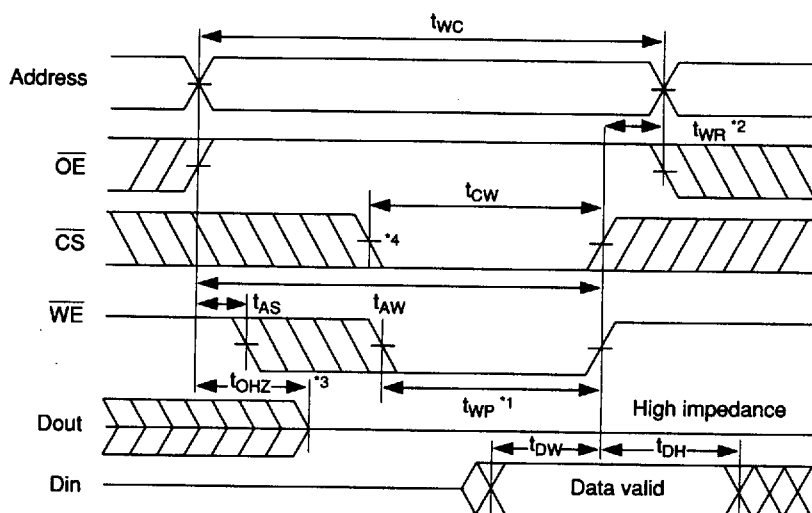


- Notes: 1. $\overline{WE}$ is high for read cycle.
 2. Device is continuously selected, $\overline{CS} = V_{IL}$.
 3. $\overline{OE} = V_{IL}$.

Read Cycle 3

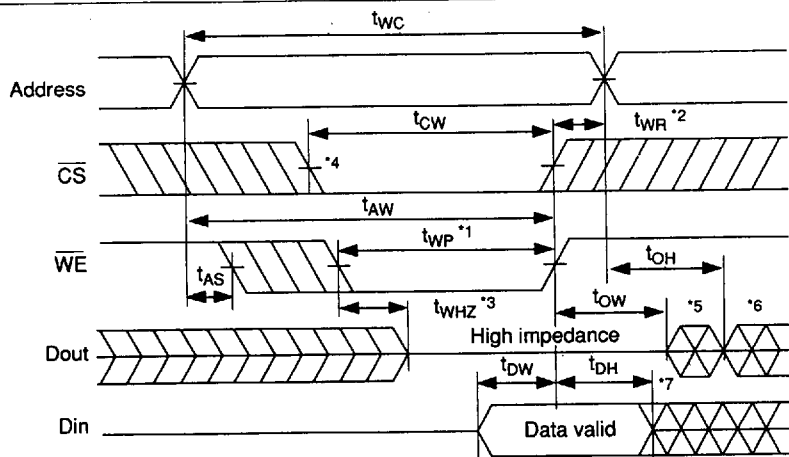


- Notes: 1. $\overline{WE}$ is high for read cycle.
 2. Address valid prior to or coincident with $\overline{CS}$ transition low.
 3. $\overline{OE} = V_{IL}$.

HM6716, HM6719 SeriesHITACHI/ LOGIC/ARRAYS/MEM[™]**Write Cycle 1**

- Notes:
1. A write occurs during the overlap (t_{WP}) of a low $\overline{CS}$ and low $\overline{WE}$.
 2. t_{WR} is measured from the earlier of $\overline{CS}$ or $\overline{WE}$ going high to the end of write cycle.
 3. During this period, I/O pins are in the output state so that the input signals of opposite phase to the outputs must not be applied.
 4. If the $\overline{CS}$ low transition occurs simultaneously with the $\overline{WE}$ low transitions or after the $\overline{WE}$ transition, output remains in a high impedance state.

Write Cycle 2*8



- Notes:
1. A write occurs during the overlap (t_{WP}) of a low $\overline{CS}$ and low $\overline{WE}$.
 2. t_{WR} is measured from the earlier of $\overline{CS}$ or $\overline{WE}$ going high to the end of write cycle.
 3. During this period, I/O pins are in the output state so that the input signals of opposite phase to the outputs must not be applied.
 4. If the $\overline{CS}$ low transition occurs simultaneously with the $\overline{WE}$ low transitions or after the $\overline{WE}$ transition, output remains in a high impedance state.
 5. Dout is the same phase of write data of this write cycle.
 6. Din is the read data of next address.
 7. If $\overline{CS}$ is low during this period, I/O pins are in the output state. Then the data input signals of opposite phase to the outputs must not be applied to them.
 8. $\overline{OE}$ is continuously low ($\overline{OE} = V_{IL}$).